Measurement Report for Device, , , UID 0 -, Channel 0 (2450.000MHz)

# **Device under Test Properties**

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type	
Device,	$N/A \times N/A \times N/A$		Phone	

## **Exposure Conditions**

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		,	2450.000,	7.85	1.87	39.9
HSI			0	0			

# **Hardware Setup**

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date	
Twin-SAM V8.0 (30deg probe tilt) -	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7383, 2023-06-05	DAE3 Sn427, 2023-05-17	
хххх	2024-Jan-03			

## **Scan Setup**

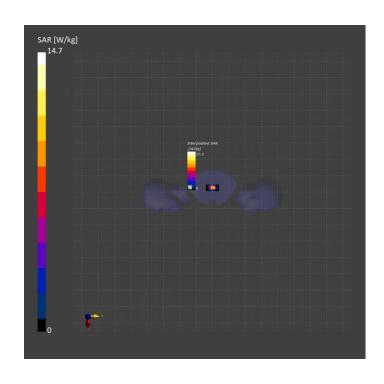
	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

#### **Measurement Results**

	Area Scan	Zoom Scan
Date	2024-01-03, 08:31	2024-01-03, 08:38
psSAR1g [W/kg]	13.1	13.6
psSAR10g [W/kg]	6.18	6.52
Power Drift [dB]	-0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.2
Dist 3dB Peak [mm]		9.5

## Warning(s) / Error(s)

Details Area Scan Zoom Scan



Measurement Report for Device, , , UID 0 -, Channel 0 (5250.000MHz)

# **Device under Test Properties**

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type	
Device.	N/A x N/A x N/A		Phone	

## **Exposure Conditions**

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		,	5250.000,	5.57	4.59	36.4
HSI			0	0			

## **Hardware Setup**

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date	
Twin-SAM V8.0 (30deg probe tilt) -	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7383, 2023-06-05	DAE3 Sn427, 2023-05-17	
хххх	2024-Jan-03			

## **Scan Setup**

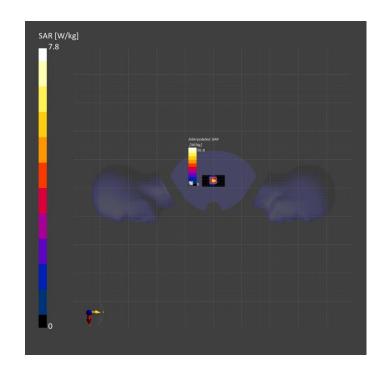
	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

#### **Measurement Results**

	Area Scan	Zoom Scan
Date	2024-01-03, 08:45	2024-01-03, 08:54
psSAR1g [W/kg]	7.12	7.95
psSAR10g [W/kg]	2.01	2.23
Power Drift [dB]	0.02	0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.6
Dist 3dB Peak [mm]		7.4

## Warning(s) / Error(s)

Details Area Scan Zoom Scan



Measurement Report for Device, , , UID 0 -, Channel 0 (5600.000MHz)

# **Device under Test Properties**

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

## **Exposure Conditions**

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		,	5600.000,	5.01	4.97	35.6
HSI			0	0			

## **Hardware Setup**

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7383, 2023-06-05	DAE3 Sn427, 2023-05-17
хххх	2024-Jan-03		

## **Scan Setup**

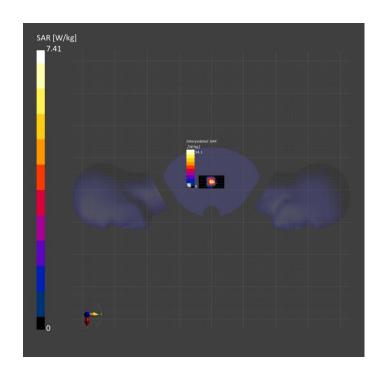
	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

#### **Measurement Results**

	Area Scan	Zoom Scan
Date	2024-01-03, 09:02	2024-01-03, 09:11
psSAR1g [W/kg]	7.45	8.29
psSAR10g [W/kg]	2.12	2.25
Power Drift [dB]	0.02	0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.0
Dist 3dB Peak [mm]		7.6

## Warning(s) / Error(s)

Details Area Scan Zoom Scan



Measurement Report for Device, , , UID 0 -, Channel 0 (5750.000MHz)

# **Device under Test Properties**

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type	
Device.	N/A x N/A x N/A		Phone	

## **Exposure Conditions**

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		,	5750.000,	5.08	5.15	35.4
HSI			0	0			

## **Hardware Setup**

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7383, 2023-06-05	DAE3 Sn427, 2023-05-17
хххх	2024-Jan-03		

## **Scan Setup**

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

#### **Measurement Results**

	Area Scan	Zoom Scan
Date	2024-01-03, 09:18	2024-01-03, 09:26
psSAR1g [W/kg]	7.25	7.56
psSAR10g [W/kg]	2.13	2.19
Power Drift [dB]	0.00	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		60.7
Dist 3dB Peak [mm]		7.6

## Warning(s) / Error(s)

Details Area Scan Zoom Scan

